



RIGOL

DHO1000 Series

Digital Oscilloscope

Performance Verification

May.2025

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1 Safety Requirement

1.1 General Safety Summary

Please review the following safety precautions carefully before putting the instrument into operation so as to avoid any personal injury or damage to the instrument and any product connected to it. To prevent potential hazards, please follow the instructions specified in this manual to use the instrument properly.

- **Use Proper Power Cord.**

Only the power cord designed for the instrument and authorized for use within the local country could be used.

- **Ground the Instrument.**

The instrument is grounded through the Protective Earth lead of the power cord. To avoid electric shock, connect the earth terminal of the power cord to the Protective Earth terminal before connecting any input or output terminals.

- **Connect the Probe Correctly.**

If a probe is used, the probe ground lead must be connected to earth ground. Do not connect the ground lead to high voltage. Improper way of connection could result in dangerous voltages being present on the connectors, controls or other surfaces of the oscilloscope and probes, which will cause potential hazards for operators.

- **Observe All Terminal Ratings.**

To avoid fire or shock hazard, observe all ratings and markers on the instrument and check your manual for more information about ratings before connecting the instrument.

- **Use Proper Overvoltage Protection.**

Ensure that no overvoltage (such as that caused by a bolt of lightning) can reach the product. Otherwise, the operator might be exposed to the danger of an electric shock.

- **Do Not Operate Without Covers.**

Do not operate the instrument with covers or panels removed.

- **Do Not Insert Objects into the Air Outlet.**

Do not insert objects into the air outlet, as doing so may cause damage to the instrument.

- **Use Proper Fuse.**

Please use the specified fuses.

- **Avoid Circuit or Wire Exposure.**

Do not touch exposed junctions and components when the unit is powered on.

- **Do Not Operate With Suspected Failures.**

If you suspect that any damage may occur to the instrument, have it inspected by RIGOL authorized personnel before further operations. Any maintenance, adjustment or replacement especially to circuits or accessories must be performed by RIGOL authorized personnel.

- **Provide Adequate Ventilation.**

Inadequate ventilation may cause an increase of temperature in the instrument, which would cause damage to the instrument. So please keep the instrument well ventilated and inspect the air outlet and the fan regularly.

- **Do Not Operate in Wet Conditions.**

To avoid short circuit inside the instrument or electric shock, never operate the instrument in a humid environment.

- **Do Not Operate in an Explosive Atmosphere.**

To avoid personal injuries or damage to the instrument, never operate the instrument in an explosive atmosphere.

- **Keep Product Surfaces Clean and Dry.**

To avoid dust or moisture from affecting the performance of the instrument, keep the surfaces of the instrument clean and dry.

- **Prevent Electrostatic Impact.**

Operate the instrument in an electrostatic discharge protective environment to avoid damage induced by static discharges. Always ground both the internal and external conductors of cables to release static before making connections.

- **Proper Use of Battery.**

Do not expose the battery (if available) to high temperature or fire. Keep it out of the reach of children. Improper change of battery (note: lithium battery) may cause explosion. Use the RIGOL specified battery only.

- **Handle with Caution.**

Please handle with care during transportation to avoid damage to keys, knob interfaces and other parts on the panels.

1.2 Safety Notices and Symbols

Safety Notices in this Manual:



WARNING

Indicates a potentially hazardous situation or practice which, if not avoided, will result in serious injury or death.



CAUTION

Indicates a potentially hazardous situation or practice which, if not avoided, could result in damage to the product or loss of important data.

Safety Notices on the Product:

- **DANGER**

It calls attention to an operation, if not correctly performed, could result in injury or hazard immediately.

- **WARNING**

It calls attention to an operation, if not correctly performed, could result in potential injury or hazard.

- **CAUTION**

It calls attention to an operation, if not correctly performed, could result in damage to the product or other devices connected to the product.

Safety Symbols on the Product:



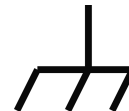
**Hazardous
Voltage**



Safety Warning



**Protective Earth
Terminal**



Chassis Ground



Test Ground

2 Specifications

This chapter lists the technical specifications of the DHO1000 series oscilloscope.

DHO1000 series digital oscilloscope achieves 2 GSa/s sample rate, a fast waveform capture rate of 1,500,000 wfms/s with the UltraAcquire mode, 100 Mpts memory depth, 12-bit vertical resolution, all combined with excellent noise floor performance and vertical accuracy to meet your requirements for more accurate measurements, bringing extraordinary T&M experience for you.

To meet specifications, these conditions must be met:

- The instrument must have been calibrated in an ambient temperature between 18°C and 28°C.
- The instrument must be operating within the environmental limits. (For the specific environment requirements, refer to *DHO1000 Data Sheet*).
- The instrument must be powered from a source that meets the requirement for the power supply. (For the power specifications, refer to *DHO1000 Data Sheet*).
- The instrument must have been operating continuously for at least 30 minutes within the specified operating temperature range.

The following table shows some of the technical specifications of DHO1072, DHO1074, DHO1102, DHO1104, DHO1202, and DHO1204. For other technical specifications of DHO1000, please refer to *DHO1000 Data Sheet*.

Table 2.1 Specifications

Overview of the DHO1000 Series Technical Specifications						
Model	DHO1072	DHO1074	DHO1102	DHO1104	DHO1202	DHO1204
Analog Bandwidth (-3 dB)	70 MHz	70 MHz	100 MHz	100 MHz	200 MHz	200 MHz
No. of Input Channels	2+EXT	4+EXT	2+EXT	4+EXT	2+EXT	4+EXT
Input Coupling	DC, AC, or GND					
Input Impedance	1 MΩ ± 1%					
Sampling Mode	Real-time sampling					

Overview of the DHO1000 Series Technical Specifications

Bandwidth Limit	20 MHz, FULL; selectable for each channel
Max. Analog Channel Sample Rate	2-channel model: 2 GSa/s (single channel ^[1]), 1 GSa/s (all channels ^[3]) 4-channel model: 2 GSa/s (single channel ^[1]), 1 GSa/s (half channels ^[2]), 500 MSa/s (all channels ^[3])
Standard Memory Depth	2-channel model: 50 Mpts (single channel ^[1]), 25 Mpts (all channels ^[3]) 4-channel model: 50 Mpts (single channel ^[1]), 25 Mpts (half channels ^[2]), 12.5 Mpts (all channels ^[3])
Optional Memory Depth	2-channel model: 100 Mpts (single channel ^[1]), 50 Mpts (all channels ^[3]) 4-channel model: 100 Mpts (single channel ^[1]), 50 Mpts (half channels ^[2]), 25 Mpts (all channels ^[3])
Max. Waveform Capture Rate	50,000 wfms/s (Vector Mode) 1,500,000 wfms/s (UltraAcquire Mode)
Vertical Resolution	12 bits
DC Gain Accuracy	±2% Full Scale
Time Base Accuracy	±5 ppm ± 1 ppm/year
Trigger Source	Analog channel (1-4), EXT TRIG, and AC Line

NOTE

[1]: If any one of the channels is enabled, it is called single channel mode.

[2]: For 4-channel models, if two of the channels are enabled, it is called half channels mode.

[3]: For 2-channel models, if two channels are enabled, it is called all channels mode. For 4-channel models, if any three channels or all four channels are enabled, it is called all channels mode.

3 Document Overview

This manual is designed to guide you to properly test the performance specifications of RIGOL DHO1000 series digital oscilloscope. For the operation methods mentioned in the test procedures, refer to User Guide of this product.



TIP

For the latest version of this manual, download it from the official website of RIGOL (<http://www.rigol.com>).

Publication Number

PVA32101-1110

Software Version

Software upgrade might change or add product features. Please acquire the latest version of the manual from RIGOL website or contact RIGOL to upgrade the software.

Format Conventions in this Manual

1. Key

The front panel key is denoted by the menu key icon. For example, indicates the "Default" key.




2. Menu

The menu item is denoted by the format of "Menu Name (Bold) + Character Shading" in the manual. For example, **Setup** indicates the "Setup" sub-menu under the "Utility" function menu. You can click or tap **Setup** to access the "Setup" menu.

3. Operation Procedures

The next step of the operation is denoted by ">" in the manual. For example,



> **Storage** indicates first clicking or tapping  and then clicking or tapping **Storage**.

4. Connector

The front/rear panel connector is denoted by "Brackets + Connector Name (Bold)", for example, **[AUX OUT]**.

Content Conventions in this Manual

DHO1000 series digital oscilloscope includes the following models. Four-channel models and two-channel models share the identical operation methods. Unless otherwise specified, this manual takes the four-channel model DHO1104 as an example to illustrate the methods for the performance verification of DHO1000 series.

Model	Max. Analog Bandwidth	No. of Analog Channels
DHO1072	70 MHz	2
DHO1074	70 MHz	4
DHO1102	100 MHz	2
DHO1104	100 MHz	4
DHO1202	200 MHz	2
DHO1204	200 MHz	4



4 Overview

4.1 Test Preparations

Before the test, make the following preparations.

1. Self-test
2. Warm-up (make sure that the instrument has been running for at least 30 minutes)
3. Self-calibration

Self-test

After the instrument is connected to the power source, press the power key  at the lower-left corner of the front panel to power on the instrument. You can also click or tap  > **Utility** > **Setup**. Then select "Switch On" for the **Power status** menu. After the instrument is connected to power source, it will start directly.

During the start-up process, the instrument performs a series of self-tests. After the self-test, the splash screen is displayed.

If the oscilloscope cannot start normally, refer to the "Troubleshooting" chapter in *DHO1000 User Guide* to locate the problem and resolve it. Do not perform self-calibration or performance tests until the instrument passes the self-test.

Self-calibration

The self-calibration program can quickly make the oscilloscope work in an optimal state to get the precise measurement results. You can perform self-calibration at any time, especially when the changes of the ambient temperature reach or above 5°C. Make sure that the oscilloscope has been warmed up or operating for more than 30 minutes before the self-calibration.

1. Disconnect all the input channels.
2. In "Utility" menu, click or tap **SelfCal**. The self-calibration interface will be displayed as shown below.

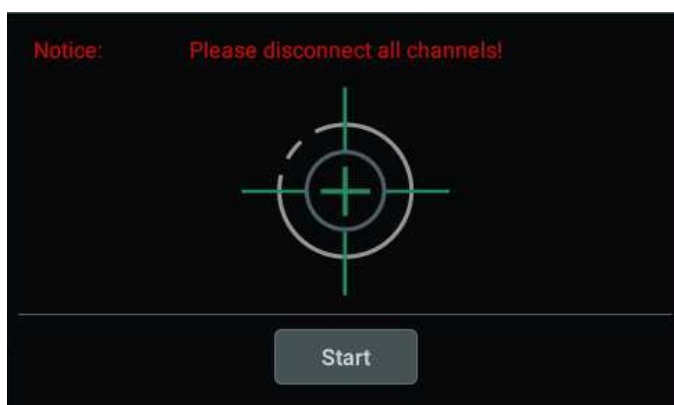


Figure 4.1 Self-calibration Menu

- Click or tap **Start**, and then the oscilloscope will start to execute the self-calibration program.
 - After starting the self-calibration program, you can click or tap **Exit** to cancel self-calibration operation at any time.
3. After completing the self-calibration, restart the oscilloscope. In the **Horizontal** menu, select "Average" for the **Acquisition** item. Then click or tap the input field of the Averages item to set the number of averages to 16 with the pop-up numeric keypad.
 4. Set the vertical scale of each channel to 2 mV/div and view the offset of the waveform of each channel. If the offset is greater than 0.5 div, check whether there are interference signals around you and whether the power source is well grounded. After that, perform self-calibration again.
 5. Click or tap **Close** to close the self-calibration information window.

4.2 Test Result Record

Record and keep the test result of each test. In the final chapter of this manual, a test result record form is provided. The form lists all the test items and their corresponding performance limits as well as spaces for users to record the test results.



TIP

It is recommended that users photocopy the test record form before each test and record the test results in the copy so that the form can be used repeatedly.

4.3 Specifications

The specification of each test item is provided in this manual. For other technical parameters, refer to *DHO1000 Data Sheet* (download it from RIGOL website: www.rigol.com).



TIP

All the specifications are valid only when the oscilloscope has been warmed up for more than 30 minutes within the specified operating temperature range (18°C to 28°C).

5 Performance Verification Test

This chapter takes DHO1104 as an example to illustrate the performance verification test methods and procedures of DHO1000 series digital oscilloscope. This manual recommends the following test devices. You can also use other devices that fulfill the "Specification" in [Table 5.1 Test Devices](#).

Table 5.1 Test Devices

Device	Specification	Recommended Model
Oscilloscope Calibrator	DC: ± 1 mV to ± 200 V, $\pm(0.025\% + 25 \mu\text{V})$ Steady-state Sine: (5 mV~5 V) @ (0.1 Hz~3.2 GHz), $\pm 1.5\%$ Resistance: $\pm 0.1\%$ Capacitance: 1 pF to 35 pF, $\pm 2\% \pm 0.25$ pF	Fluke 9500B



TIP

1. Make sure that the oscilloscope passes the self-test and the self-calibration is performed before executing the performance verification tests.
2. Make sure that the oscilloscope has been warmed up for at least 30 minutes before executing any of the following tests.
3. Please reset the instrument to the factory setting before or after executing any of the following tests.

5.1 Random Noise Test

This test tests the random noise for each channel in the Normal acquisition mode.

5.1.1 Specification

Noise Floor, Typical (2 GSa/s Sample Rate, 1 Mpts Memory Depth, 20 μs Time Base)			
	DHO1072/DHO1074	DHO1102/DHO1104	DHO1204/DHO1202
500 $\mu\text{V}/\text{div}$	62 μV_{rms}	66 μV_{rms}	75 μV_{rms}
1 mV/div	64 μV_{rms}	68 μV_{rms}	77 μV_{rms}
2 mV/div	68 μV_{rms}	76 μV_{rms}	77 μV_{rms}
5 mV/div	74 μV_{rms}	82 μV_{rms}	95 μV_{rms}
10 mV/div	76 μV_{rms}	87 μV_{rms}	101 μV_{rms}
20 mV/div	97 μV_{rms}	101 μV_{rms}	144 μV_{rms}

Noise Floor, Typical (2 GSa/s Sample Rate, 1 Mpts Memory Depth, 20 μ s Time Base)


50 mV/div	134 μ V _{rms}	162 μ V _{rms}	305 μ V _{rms}
100 mV/div	974 μ V _{rms}	1.1 mV _{rms}	1.4 mV _{rms}
200 mV/div	1.2 mV _{rms}	1.3 mV _{rms}	1.8 mV _{rms}
500 mV/div	3.6 mV _{rms}	4.3 mV _{rms}	6 mV _{rms}
1 V/div	4.3 mV _{rms}	5 mV _{rms}	7.9 mV _{rms}
2 V/div	6 mV _{rms}	7 mV _{rms}	13 mV _{rms}
5 V/div	30 mV _{rms}	34.5 mV _{rms}	49 mV _{rms}
10 V/div	36 mV _{rms}	44 mV _{rms}	74 mV _{rms}

5.1.2 Test Procedures



TIP

Before test, disconnect the instrument from all the signal generators and keep the noise sources away from the instrument.

1. Press the front-panel  key to restore the oscilloscope to the default settings.
2. By default, the acquisition mode is "Normal", the sample rate is 2 GSa/s, the horizontal time base is 20 μ s, and the memory depth is 1 Mpts.
3. Click or tap the trigger label at the top of the screen. Set the trigger source to CH1. Set the trigger level to the maximum to prevent the signals from being triggered by mistake.
4. In the **Measure** menu, click or tap **Vertical** measurement item to select "AC.RMS". The AC.RMS measurement result is displayed at the right section of the screen.
5. Click or tap the "Result" sidebar and then select Setting. Set **Count** to 100.
6. When the statistics count in the "Result" sidebar shows 100, read and record the AC.RMS value.
7. For the parameter setting, refer to *Test Record From*. Repeat Step 1-7 and test the AC.RMS value for different vertical scales, bandwidths. The test results should be less than the max. value in the record form.

5.1.3 Test Record From

Vertical Scale	Bandwidth	Test Result	Maximum			Pass/Fail
			DHO1072/DHO1074	DHO1102/DHO1104	DHO1204/DHO1202	
500 μ V/div	Full BW		62 μ V _{rms}	66 μ V _{rms}	75 μ V _{rms}	
1 mV/div	Full BW		64 μ V _{rms}	68 μ V _{rms}	77 μ V _{rms}	

Vertical Scale	Bandwidth	Test Result	Maximum			Pass/Fail
			DHO1072/ DHO1074	DHO1102/ DHO1104	DHO1204/ DHO1202	
2 mV/div	Full BW		68 μV_{rms}	76 μV_{rms}	77 μV_{rms}	
5 mV/div	Full BW		74 μV_{rms}	82 μV_{rms}	95 μV_{rms}	
10 mV/div	Full BW		76 μV_{rms}	87 μV_{rms}	101 μV_{rms}	
20 mV/div	Full BW		97 μV_{rms}	101 μV_{rms}	144 μV_{rms}	
50 mV/div	Full BW		134 μV_{rms}	162 μV_{rms}	305 μV_{rms}	
100 mV/div	Full BW		974 μV_{rms}	1.1 mV _{rms}	1.4 mV _{rms}	
200 mV/div	Full BW		1.2 mV _{rms}	1.3 mV _{rms}	1.8 mV _{rms}	
500 mV/div	Full BW		3.6 mV _{rms}	4.3 mV _{rms}	6 mV _{rms}	
1 V/div	Full BW		4.3 mV _{rms}	5 mV _{rms}	7.9 mV _{rms}	
2 V/div	Full BW		6 mV _{rms}	7 mV _{rms}	13 mV _{rms}	
5 V/div	Full BW		30 mV _{rms}	34.5 mV _{rms}	49 mV _{rms}	
10 V/div	Full BW		36 mV _{rms}	44 mV _{rms}	74 mV _{rms}	

5.2 Impedance Test

5.2.1 Specification

Input Impedance	
Analog Channel	0.99 M Ω to 1.01 M Ω

5.2.2 Test Connection Diagram

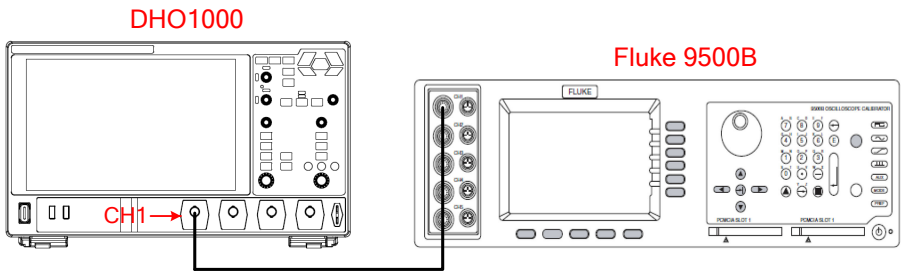



Figure 5.1 Input Impedance Test Connection Diagram

5.2.3 Test Procedures



WARNING
Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.1*.
2. Configure the oscilloscope:
 - a. To enable the channel, perform any of the following operations:
 - Click or tap the channel status label at the bottom of the screen to enable CH1.
 - Press the front-panel  key to enable the channel.
 - In the **Vertical** menu, select the CH1 tab. Select **ON** for the **Display** item to turn CH1 on.
 - b. Set the vertical scale of CH1 to 50 mV/div.
3. Turn on Fluke 9500B; set its impedance to 1 MΩ and select the resistance measurement function. Read and record the resistance measured.
4. Adjust the vertical scale of CH1 to 500 mV/div; read and record the resistance measured.
5. Turn off CH1. Measure the resistances of CH2, CH3, and CH4 respectively using the method above and record the measurement results.

5.2.4 Test Record From

Channel	Vertical Scale	Test Result	Limit	Pass/Fail
CH1	50 mV/div		0.99 MΩ to 1.01 MΩ	
	500 mV/div		0.99 MΩ to 1.01 MΩ	
CH2	50 mV/div		0.99 MΩ to 1.01 MΩ	
	500 mV/div		0.99 MΩ to 1.01 MΩ	
CH3	50 mV/div		0.99 MΩ to 1.01 MΩ	
	500 mV/div		0.99 MΩ to 1.01 MΩ	
CH4	50 mV/div		0.99 MΩ to 1.01 MΩ	
	500 mV/div		0.99 MΩ to 1.01 MΩ	

5.3 Input Capacitance Test

5.3.1 Specification

Input Capacitance	
Specification	19 pF ± 3 pF

5.3.2 Test Connection Diagram

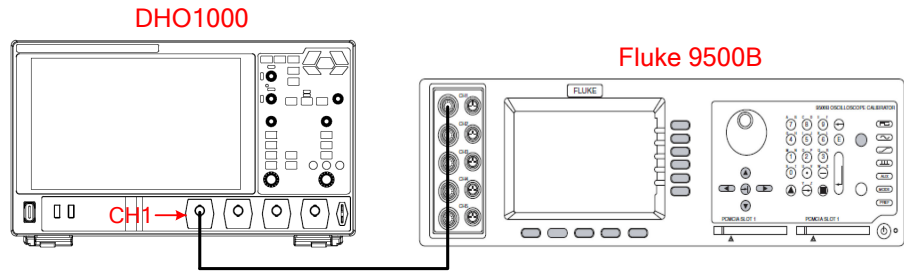


Figure 5.2 Input Capacitance Test Connection Diagram

5.3.3 Test Procedures



WARNING

Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.2*.
2. Configure the oscilloscope:
 - a. To enable CH1, perform any of the following operations:
 - Click or tap the channel status label at the bottom of the screen to enable CH1.
 - Press the front-panel 1 key to enable the channel.
 - In the **Vertical** menu, select the CH1 tab. Select **ON** for the **Display** item to turn CH1 on.
 - b. Set the vertical scale of CH1 to 50 mV/div.
3. Turn on Fluke 9500B; set its impedance to 1 MΩ and select the capacitance measurement function. Read and record the capacitance measured.
4. Adjust the vertical scale of CH1 to 500 mV/div; read and record the capacitance measured.
5. Turn off CH1. Measure the capacitances of CH2, CH3, and CH4 respectively using the method above and record the measurement results.

5.3.4 Test Record From

Channel	Vertical Scale	Test Result	Limit	Pass/Fail
CH1	50 mV/div		19 pF ± 3 pF	
	500 mV/div		19 pF ± 3 pF	

Channel	Vertical Scale	Test Result	Limit	Pass/Fail
CH2	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	
CH3	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	
CH4	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	

5.4 DC Gain Accuracy Test

5.4.1 Specification

DC Gain Accuracy	
Specification	$\pm 2\% \times \text{Full Scale}$

5.4.2 Test Connection Diagram

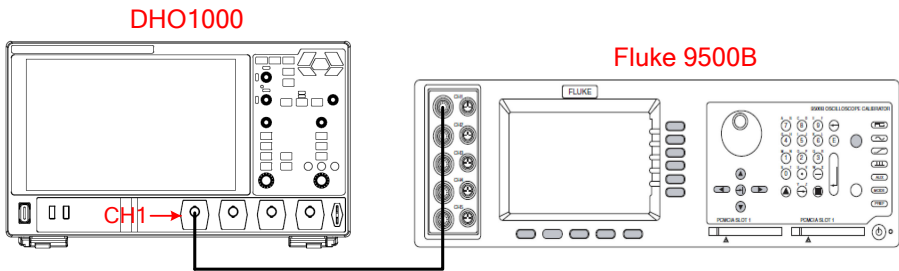


Figure 5.3 DC Gain Accuracy Test Connection Diagram

5.4.3 Test Procedures



WARNING

Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.3*.
2. Set the impedance of Fluke 9500B to 1 M Ω .
3. Output a DC signal with +3 mVdc voltage (Vout1) via Fluke 9500B.
4. Configure the oscilloscope:
 - a. To enable CH1, perform any of the following operations:
 - Click or tap the channel status label at the bottom of the screen to enable CH1.

- Press the front-panel 1 key to enable the channel.
 - In the **Vertical** menu, select the CH1 tab. Select **ON** for the **Display** item to turn CH1 on.
- b.** Click or tap the channel status label at the bottom of the screen. Then the **Vertical** menu is displayed. Click or tap **Probe** to enter the **Probe** setting menu. Set the probe attenuation ratio to "1X".
 - c.** Set the vertical scale to 1 mV/div.
 - d.** Set the horizontal time base to 1 μ s/div.
 - e.** Set the vertical offset to 0.
 - f.** In the **Horizontal** menu, select "Average" for the **Acquisition** item. Then click or tap the input field of **Averages** to set the number of averages to 32 with the pop-up numeric keypad.
 - g.** Adjust the trigger level to prevent the signals from being triggered by mistake.
- 5.** In the **Measure** menu, click or tap **Vertical** measurement item to select "Vavg". The Vavg result is displayed in the "Result" sidebar at the right side of the screen. Read and record the measurement result of Vavg1.
 - 6.** Adjust Fluke 9500B to make it output a DC signal with -3 mVdc voltage (Vout2).
 - 7.** Enable the average measurement function. Read and record Vavg2.
 - 8.** Calculate the relative error of this vertical scale: $|(V_{avg1} - V_{avg2}) - (V_{out1} - V_{out2})| / \text{Full Scale} \times 100\%$.
 - 9.** Keep the other settings of the oscilloscope unchanged.
 - a.** Set the vertical scale to 2 mV/div, 5 mV/div, 10 mV/div, 20 mV/div, 50 mV/div, 100 mV/div, 200 mV/div, 500 mV/div, 1 V/div, 2 V/div, 5 V/div, and 10 V/div.
 - b.** Adjust the output voltage of Fluke 9500B to 3 x the current vertical scale and -3 x the current vertical scale respectively.
 - c.** Repeat Step 3-7 and record the test results.
 - d.** Calculate the relative error of each vertical scale: $|(V_{avg1} - V_{avg2}) - (V_{out1} - V_{out2})| / \text{Full Scale} \times 100\%$.
 - 10.** Turn off CH1. Test the relative error of each scale of CH2, CH3, and CH4 respectively using the method above and record the test results.

5.4.4 Test Record From

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		Vavg1	Vavg2	Calculation Result ^[1]		
CH1	1 mV/div				≤2%	
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	
	10 V/div				≤2%	
CH2	1 mV/div				≤2%	
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	
	10 V/div				≤2%	
CH3	1 mV/div				≤2%	
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		Vavg1	Vavg2	Calculation Result ^[1]		
	10 V/div				≤2%	
CH4	1 mV/div				≤2%	
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	
	10 V/div				≤2%	

NOTE

[1]: The calculation formula is $|(V_{avg1} - V_{avg2}) - (V_{out1} - V_{out2})| / \text{Full Scale} \times 100\%$; wherein, V_{out1} is 3 x the current vertical scale and V_{out2} is -3 x the current vertical scale.

5.5 DC Offset Accuracy Test

5.5.1 Specification

DC Offset Accuracy	
Specification	$\leq 200 \text{ mV/div } (\pm 0.1 \text{ div} \pm 2 \text{ mV} \pm 1.5\% \text{ of the offset value})$ $> 200 \text{ mV/div } (\pm 0.1 \text{ div} \pm 2 \text{ mV} \pm 1.0\% \text{ of the offset value})$

5.5.2 Test Connection Diagram

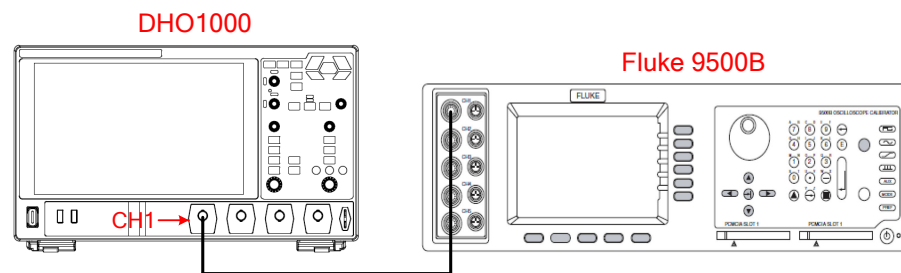



Figure 5.4 DC Offset Accuracy Test Connection Diagram

5.5.3 Test Procedures



WARNING

Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.4*.
2. Set the impedance of Fluke 9500B to 1 M Ω .
3. Configure the oscilloscope:
 - a. Press the front-panel  key to restore the oscilloscope to the default settings.
 - b. Set the vertical scale to 500 μ V/div.
 - c. Click or tap the **BW Limit** drop-down button to select "20 M".
 - d. Set the offset to 1 V, as shown in *Test Record From*. Close the Vertical menu.
 - e. Click or tap the horizontal label at the top of the screen. Then the **Horizontal** menu is displayed. In this menu, set the time base to 1 ms/div. Select "Average" for the **Acquisition** item. Then click or tap the input field of the **Averages** item to set the number of averages to 16 with the pop-up numeric keypad. Close the Horizontal menu.
 - f. Click or tap the trigger label at the top of the screen. Set the trigger source to AC Line.
 - g. Adjust the trigger level to prevent the signals from being triggered by mistake.
4. Set the output of Fluke 9500B to -1 V.

5. In the **Measure** menu, click or tap **Vertical** measurement item to select "Vavg". The Vavg result is displayed in the "Result" sidebar at the right side of the screen. Read and record the measurement result.
6. Set the vertical offset of the oscilloscope to 0 V.
7. Set the output of Fluke 9500B to 0 V. Read the value from the "Result" sidebar and record the measurement result.
8. Repeat Step 2-7. Measure and record the average results of different vertical scales and offsets according to *Test Record From*.

5.5.4 Test Record From

Channel Setting	Vertical Scale	Offset	Test Result	Min.	Max.
CH1, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH2, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH3, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV

Channel Setting	Vertical Scale	Offset	Test Result	Min.	Max.
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH4, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V

5.6 Bandwidth Test

5.6.1 Specification

Bandwidth			
Amplitude Loss ^[1]	DHO1072/ DHO1074	70 MHz	-3 dB, all channels mode
	DHO1104/ DHO1102	100 MHz	-3 dB, all channels mode
	DHO1202/ DHO1204	200 MHz	-3 dB, all channels mode

NOTE

[1]: Amplitude Loss (dB) = $20 \times \lg(V_{rms2}/V_{rms1})$; wherein, V_{rms1} is the measurement result of amplitude effective value at 1MHz and V_{rms2} is the measurement result of amplitude effective value at full bandwidth.

5.6.2 Test Connection Diagram

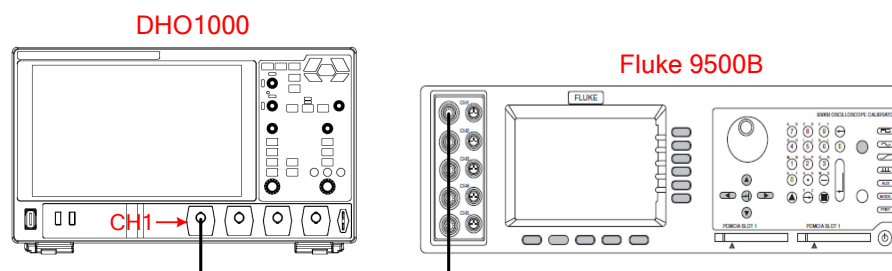


Figure 5.5 Bandwidth Test Connection Diagram

5.6.3 Test Procedures



WARNING

Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.5*.
2. Turn on Fluke 9500B and set its impedance to 1 MΩ.
3. Configure the oscilloscope:
 - a. To enable CH1, perform any of the following operations:
 - Click or tap the channel status label at the bottom of the screen to enable CH1.
 - Press the front-panel 1 key to enable the channel.
 - In the **Vertical** menu, select the CH1 tab. Select **ON** for the **Display** item to turn CH1 on.
 - b. Click or tap the channel status label of CH1 at the bottom of the screen. Then the **Vertical** menu is displayed. Click or tap **Probe** to enter the **Probe** setting menu. Set the probe attenuation ratio to "1X".
 - c. Set the vertical scale to 50 mV/div.
 - d. Set the vertical offset to 0 V. Then close the **Vertical** menu.
 - e. Click or tap the horizontal label at the top of the screen. Then the **Horizontal** menu is displayed. In this menu, you can set the horizontal time base to 500 ns/div.
 - f. Set the horizontal position to 0 s. Close the **Horizontal** menu.
 - g. Set the trigger level to 0 V.

4. Output a Sine signal with 1 MHz frequency and 6 div amplitude (e.g. 50 mV/div vertical scale, 300 mVpp amplitude Sine signal) via the Fluke 9500B. Adjust the horizontal time base to display five cycles of the waveforms on the screen.
5. In the **Measure** menu, click or tap **Vertical** measurement item to select "AC.RMS". The AC.RMS measurement result is displayed in the "Result" sidebar at the right section of the screen. Read the value and record the measurement result as Vrms1.
6. Use the Fluke 9500B to output a Sine signal with the maximum bandwidth of the oscilloscope and 6 div amplitude. The bandwidth frequency differs for different oscilloscope models. For details, please refer to *Specification*. Adjust the horizontal time base to display five cycles of the waveforms on the screen.
7. Check the AC.RMS "Result" sidebar at the right section of the screen. Read and record the data as Vrms2.
8. Calculate the amplitude loss with the following formula: Amplitude Loss (dB) = $20 \times \lg(V_{rms2}/V_{rms1})$.
9. Repeat Step 2-7. Measure Vrms1 and Vrms2, and calculate the amplitude loss of 500 mV/div vertical scale.
10. Turn off CH1. Measure CH2, CH3, and CH4 respectively using the method above and record the measurement results.

5.6.4 Test Record From

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		V _{rms1}	V _{rms2}	Amplitude Loss ^[1]		
CH1	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH2	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH3	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH4	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	

NOTE

[1]: Amplitude Loss (dB) = $20 \times \lg(V_{\text{rms}2}/V_{\text{rms}1})$; wherein, $V_{\text{rms}1}$ is the measurement result of amplitude effective value at 1MHz and $V_{\text{rms}2}$ is the measurement result of amplitude effective value at full bandwidth.

5.7 Time Base Accuracy Test

5.7.1 Specification

Time Base Accuracy ^[1]	
Specification	$\pm(5 \text{ ppm} + 1 \text{ ppm}^{[2]}/\text{year} \times \text{Number of Years that the Instrument Has Been Used}^{[3]})$

NOTE

[1]: Typical.

[2]: Clock Drift.

[3]: For the number of years that the instrument has been used, please calculate it according to the date in the verification certificate provided when the instrument leaves factory.

5.7.2 Test Connection Diagram

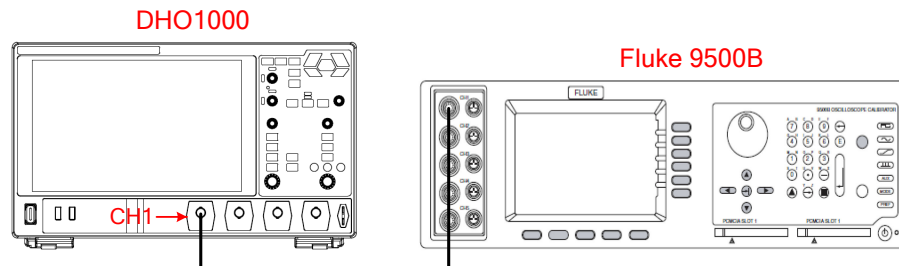


Figure 5.6 Time Base Accuracy Test Connection Diagram




5.7.3 Test Procedures



WARNING

Before connecting, disconnecting, or moving the test hookup, disable the output of the signal generator to avoid causing the dangerous voltage.

1. Connect the active head of Fluke 9500B to CH1 of the oscilloscope, as shown in *Figure 5.6*.
2. Output a Sine signal with 10 MHz frequency and 1 Vpp amplitude via Fluke 9500B.
3. Configure the oscilloscope:

- a. Press the front-panel  key to restore the oscilloscope to the default settings.
 - b. To enable CH1, perform any of the following operations:
 - Click or tap the channel status label at the bottom of the screen to enable CH1.
 - Press the front-panel  key to enable the channel.
 - In the **Vertical** menu, select the CH1 tab. Select **ON** for the **Display** item to turn CH1 on.
 - c. Click or tap the channel status label of CH1 at the bottom of the screen. Then the **Vertical** menu is displayed. Click or tap **Probe** to enter the **Probe** setting menu. Set the probe attenuation ratio to "1X".
 - d. Set the vertical scale to 200 mV/div.
 - e. Set the vertical offset to 0 V. Then close the **Vertical** menu.
 - f. Click or tap the horizontal label at the top of the screen. Then the **Horizontal** menu is displayed. In this menu, you can set the horizontal time base to 1 ns/div.
 - g. Set the horizontal position to 1 ms. Close the **Horizontal** menu.
 - h. Click or tap the trigger label at the top of the screen. Set the trigger level to 0 V.
4. Click or tap  > **Cursor**. Then the "Result" sidebar is displayed at the right section of the screen. Click or tap the "Result" sidebar and select **Setting** in the pop-up window. In the **Mode** item, select **Manual** to enable the manual cursor measurement function. Then measure the offset (ΔT) of the middle point of the signal (namely the crossing point of the rising edge of the current signal and the trigger level line) relative to the screen center and record the measurement result.
 5. Calculate the time base accuracy, namely the ratio of ΔT to the horizontal position of the oscilloscope. For example, if the offset measured is 1 ns, then the time base accuracy is 1 ns/1 ms = 1 ppm.
 6. Calculate the time base accuracy limit by using the following formula: $\pm(5 \text{ ppm} + 1 \text{ ppm/year} \times \text{Number of Years that the Instrument Has Been Used})$.

5.7.4 Test Record From

Channel	Test Result ΔT	Calculation Result ^[1]	Limit	Pass/Fail
CH1			$\pm(5 \text{ ppm} + 1 \text{ ppm/year} \times \text{Number of Years that the Instrument Has Been Used}^{[2]})$	

NOTE

[1]: Calculation Result = Test Result $\Delta T/1$ ms.

[2]: For the number of years that the instrument has been used, please calculate it according to the date in the verification certificate provided when the instrument leaves factory.

6 Appendix: Test Record Form

RIGOL DHO1000 Series Digital Oscilloscope Performance Verification Test Record Form

Model: _____ Tested by: _____ Test Date: _____

Random Noise Test Record Form

Vertical Scale	Bandwidth	Test Result	Maximum			Pass/Fail
			DHO1072/ DHO1074	DHO1102/ DHO1104	DHO1204/ DHO1202	
500 $\mu\text{V}/\text{div}$	Full BW		62 μV_{rms}	66 μV_{rms}	75 μV_{rms}	
1 mV/div	Full BW		64 μV_{rms}	68 μV_{rms}	77 μV_{rms}	
2 mV/div	Full BW		68 μV_{rms}	76 μV_{rms}	77 μV_{rms}	
5 mV/div	Full BW		74 μV_{rms}	82 μV_{rms}	95 μV_{rms}	
10 mV/div	Full BW		76 μV_{rms}	87 μV_{rms}	101 μV_{rms}	
20 mV/div	Full BW		97 μV_{rms}	101 μV_{rms}	144 μV_{rms}	
50 mV/div	Full BW		134 μV_{rms}	162 μV_{rms}	305 μV_{rms}	
100 mV/div	Full BW		974 μV_{rms}	1.1 mV _{rms}	1.4 mV _{rms}	
200 mV/div	Full BW		1.2 mV _{rms}	1.3 mV _{rms}	1.8 mV _{rms}	
500 mV/div	Full BW		3.6 mV _{rms}	4.3 mV _{rms}	6 mV _{rms}	
1 V/div	Full BW		4.3 mV _{rms}	5 mV _{rms}	7.9 mV _{rms}	
2 V/div	Full BW		6 mV _{rms}	7 mV _{rms}	13 mV _{rms}	
5 V/div	Full BW		30 mV _{rms}	34.5 mV _{rms}	49 mV _{rms}	
10 V/div	Full BW		36 mV _{rms}	44 mV _{rms}	74 mV _{rms}	

Impedance Test Record Form

Channel	Vertical Scale	Test Result	Limit	Pass/Fail
CH1	50 mV/div		0.99 M Ω to 1.01 M Ω	
	500 mV/div		0.99 M Ω to 1.01 M Ω	
CH2	50 mV/div		0.99 M Ω to 1.01 M Ω	
	500 mV/div		0.99 M Ω to 1.01 M Ω	
CH3	50 mV/div		0.99 M Ω to 1.01 M Ω	
	500 mV/div		0.99 M Ω to 1.01 M Ω	
CH4	50 mV/div		0.99 M Ω to 1.01 M Ω	
	500 mV/div		0.99 M Ω to 1.01 M Ω	

Input Capacitance Test Record Form

Channel	Vertical Scale	Test Result	Limit	Pass/Fail
CH1	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	
CH2	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	
CH3	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	
CH4	50 mV/div		19 pF \pm 3 pF	
	500 mV/div		19 pF \pm 3 pF	

DC Gain Accuracy Test Record From

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		Vavg1	Vavg2	Calculation Result ^[1]		
CH1	1 mV/div				$\leq 2\%$	
	2 mV/div				$\leq 2\%$	
	5 mV/div				$\leq 2\%$	
	10 mV/div				$\leq 2\%$	
	20 mV/div				$\leq 2\%$	
	50 mV/div				$\leq 2\%$	
	100 mV/div				$\leq 2\%$	
	200 mV/div				$\leq 2\%$	
	500 mV/div				$\leq 2\%$	
	1 V/div				$\leq 2\%$	
	2 V/div				$\leq 2\%$	
	5 V/div				$\leq 2\%$	
	10 V/div				$\leq 2\%$	
CH2	1 mV/div				$\leq 2\%$	
	2 mV/div				$\leq 2\%$	
	5 mV/div				$\leq 2\%$	
	10 mV/div				$\leq 2\%$	
	20 mV/div				$\leq 2\%$	
	50 mV/div				$\leq 2\%$	
	100 mV/div				$\leq 2\%$	
	200 mV/div				$\leq 2\%$	
	500 mV/div				$\leq 2\%$	
	1 V/div				$\leq 2\%$	
	2 V/div				$\leq 2\%$	
	5 V/div				$\leq 2\%$	
	10 V/div				$\leq 2\%$	
CH3	1 mV/div				$\leq 2\%$	

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		Vavg1	Vavg2	Calculation Result ^[1]		
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	
	10 V/div				≤2%	
CH4	1 mV/div				≤2%	
	2 mV/div				≤2%	
	5 mV/div				≤2%	
	10 mV/div				≤2%	
	20 mV/div				≤2%	
	50 mV/div				≤2%	
	100 mV/div				≤2%	
	200 mV/div				≤2%	
	500 mV/div				≤2%	
	1 V/div				≤2%	
	2 V/div				≤2%	
	5 V/div				≤2%	
	10 V/div				≤2%	

NOTE

[1]: The calculation formula is $|(V_{avg1} - V_{avg2}) - (V_{out1} - V_{out2})| / \text{Full Scale} \times 100\%$; wherein, V_{out1} is 3 x the current vertical scale and V_{out2} is -3 x the current vertical scale.

DC Offset Accuracy Test Record Form

Channel Setting	Vertical Scale	Offset	Test Result	Min.	Max.
CH1, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V

Channel Setting	Vertical Scale	Offset	Test Result	Min.	Max.
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH2, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH3, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V
CH4, 20 MHz BW	500 μ V/div	1 V		-1.02 V	-0.98 V
	500 μ V/div	0 V		-2.05 mV	2.05 mV
	500 μ V/div	-1 V		0.98 V	1.02 V
	200 mV/div	10 V		-10.17 V	-9.83 V
	200 mV/div	0 V		-22.00 mV	22.00 mV
	200 mV/div	-10 V		9.83 V	10.17 V
	1 V/div	20 V		-20.30 V	-19.70 V
	1 V/div	0 V		-102.00 mV	102.00 mV
	1 V/div	-20 V		19.70 V	20.30 V
	5 V/div	100 V		-101.50 V	-98.50 V
	5 V/div	0 V		-502.00 mV	502.00 mV
	5 V/div	-100 V		98.50 V	101.50 V

Analog Bandwidth Test Record Form

Channel	Vertical Scale	Test Result			Limit	Pass/Fail
		V _{rms1}	V _{rms2}	Amplitude Loss ^[1]		
CH1	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH2	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH3	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	
CH4	50 mV/div				-3 dB to 3 dB	
	500 mV/div				-3 dB to 3 dB	

NOTE

[1]: Amplitude Loss (dB) = $20 \times \lg(V_{rms2}/V_{rms1})$; wherein, V_{rms1} is the measurement result of amplitude effective value at 1MHz and V_{rms2} is the measurement result of amplitude effective value at full bandwidth.

Time Base Accuracy Test Record Form

Channel	Test Result ΔT	Calculation Result ^[1]	Limit	Pass/Fail
CH1			$\pm(5 \text{ ppm} + 1 \text{ ppm/year} \times \text{Number of Years that the Instrument Has Been Used}^{[2]})$	

NOTE

[1]: Calculation Result = Test Result $\Delta T/1 \text{ ms}$.

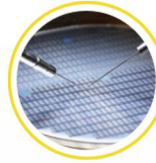
[2]: For the number of years that the instrument has been used, please calculate it according to the date in the verification certificate provided when the instrument leaves factory.

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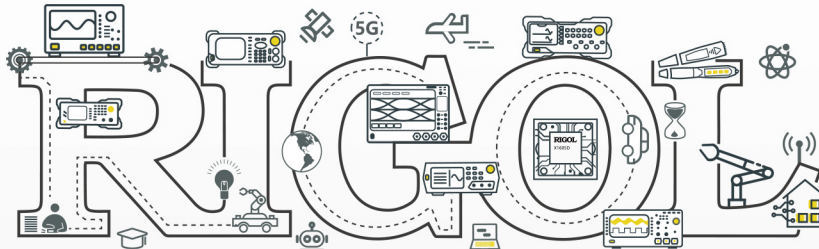
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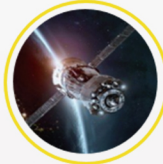


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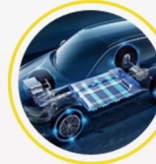


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